

TUESDAY 10TH MAY 2016

09:30 Trends in inter-laboratory method validation

Speaker : Steve Ellison, LGC Limited, UK



Dr. Ellison qualified in Chemistry at Oxford University and gained a PhD in physical organic chemistry at the University of Liverpool. Following postdoctoral research in high precision NMR techniques for characterizing isotopic and steric effects on complex equilibria at the Dyson Perrins Laboratory, Oxford, he joined the Laboratory of the Government Chemist (now LGC Limited) in the late 1980s. LGC is a forensic laboratory with referee responsibilities for regulation in foods, environment, medicines and law enforcement. In addition LGC acts as the UK National Measurement Institute for chemical and biochemical analysis. Dr Ellison is now an LGC Fellow providing technical leadership for LGC's Statistics team and additionally overseeing LGC's reference material certification activity at Teddington. . His current research interests include statistics for interlaboratory studies, reference material certification and stability, statistical methods for DNA quantitation and treatment of uncertainties and observations near zero, as well as more general development of measurement uncertainty and traceability in analytical chemistry.

Dr Ellison is a co-author of IUPAC technical Reports on Use of Recovery Information in Analytical Measurement , Single Laboratory Validation Of Methods Of Analysis, and of the latest International Harmonized Protocol for the proficiency testing of analytical chemistry laboratories. A principal author of the EURACHEM guide "Quantifying Uncertainty in Analytical Measurement", he is a recognized international expert in measurement uncertainty principles applied to analytical methods. He is a Fellow of the Royal Society of chemistry, active on the RSC Analytical Methods Committee and its Statistics sub committee, and currently convenes a Validation Issues working group within the AMC. He also contributes to a range of ISO, CEN and BSI committees involving applications of statistics applied to measurement.